

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/790,880	AKIYAMA ET AL.	
Examiner	Art Unit	
Denise Tran	2188	

SEARCHED						
SEARCHED						
Class	Subclass	Date	Examiner			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
text search (USPAT, USPGPUB,USOCR,EPOAB,JPOAB,D ERWENT, IBM-TDB)	11/21/2008	DT
711/5,118,170,128-129,104,144; 365/230.03,185.11 (text search only search history)	11/21/2008	DT
711/103,105, 167; 365/189.01 (text search only search history)	11/21/2008	DT
inventor name search	11/21/2008	DT